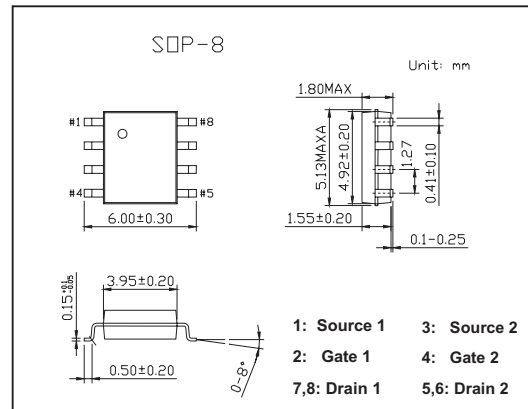
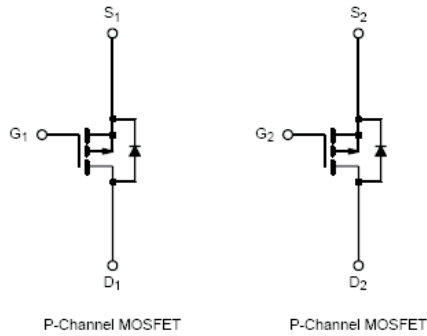


Dual P-Channel 30-V (D-S) MOSFET KI4923DY

■ Features

- TrenchFET Power MOSFETS
- Advanced High Cell Density Process



■ Absolute Maximum Ratings Ta = 25°C

Parameter	Symbol	10 secs	Steady State	Unit	
Drain-Source Voltage	V _{DS}	-30		V	
Gate-Source Voltage	V _{GS}	±20			
Continuous Drain Current (T _J = 150 °C) *	I _D	TA = 25°C	-8.3	-6.2	A
		TA = 70°C	-6.6	-5	
Pulsed Drain Current	I _{DM}	-30			
Continuous Source Current *	I _S	-1.7	-0.9		
Maximum Power Dissipation *	P _D	TA = 25°C	2	1.1	W
		TA = 70°C	1.3	0.7	
Operating Junction and Storage Temperature Range	T _J , T _{stg}	-55 to 150		°C	
Parameter	Symbol	Typ	Max	Unit	
Maximum Junction-to-Ambient*	R _{thJA}	t ≤ 10 sec	45	62.5	°C/W
		Steady-State	85	110	
Maximum Junction-to-Foot (Drain)	R _{thJF}	26	35		

* Surface Mounted on 1" X 1" FR4 Board.

KI4923DY

■ Electrical Characteristics Ta = 25°C

Parameter	Symbol	Testconditions	Min	Typ	Max	Unit
Gate Threshold Voltage	V _{GS(th)}	V _{DS} = V _{GS} , I _D = -250 μA	-1		-3	V
Gate-Body Leakage	I _{GSS}	V _{DS} = 0 V, V _{GS} = ±20 V			±100	nA
Zero Gate Voltage Drain Current	I _{DSS}	V _{DS} = -24V, V _{GS} = 0 V			-1	μA
		V _{DS} = -24V, V _{GS} = 0 V, T _J = 85°C			-25	μA
On-State Drain Current*	I _{D(on)}	V _{DS} = -5 V, V _{GS} = -10 V	-30			A
Drain-Source On-State Resistance*	r _{DS(on)}	V _{GS} = -10 V, I _D = -8.3A		0.017	0.021	Ω
		V _{GS} = -4.5 V, I _D = -6.8A		0.025	.031	Ω
Forward Transconductance*	g _{fs}	V _{DS} = -10 V, I _D = -8.3A		26		S
Schottky Diode Forward Voltage*	V _{SD}	I _S = -1.7 A, V _{GS} = 0 V		-0.8	-1.2	V
Total Gate Charge	Q _g	V _{DS} = -15V, V _{GS} = -10 V, I _D = -8.3 A		45.5	70	nC
Gate-Source Charge	Q _{gs}			6.5		nC
Gate-Drain Charge	Q _{gd}			12.6		nC
Turn-On Delay Time	t _{d(on)}	V _{DD} = -15 V, R _L = 15 Ω I _D = -1 A, V _{GEN} = -10V, R _G = 6 Ω		15	25	ns
Rise Time	t _r			10	15	ns
Turn-Off Delay Time	t _{d(off)}			135	210	ns
Fall Time	t _f			80	120	ns
Source-Drain Reverse Recovery Time	t _{rr}	I _F = -1.7 A, di/dt = 100 A/μs		70	110	ns

* Pulse test; pulse width ≤ 300 μs, duty cycle ≤ 2%.